

Application/Control No.	Applicant(s)/Patent under Reexamination
10/672,151	JACOBS ET AL.
Examiner	Art Unit
Binh X. Tran	1765

SEARCHED					
Class	Subclass	Date	Examiner		
438	710	4/28/2005	87		
438	712	4/28/2005	3		
438	714	4/28/2005	37		
438	723	4/28/2005	行		
438	724	4/28/2005	135		
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INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
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SEARCH NO (INCLUDING SEARC)
	DATE	EXMR
Updated search using EAST	4/28/2005	<i>B</i>)